

Mass volume manufacturing of 8-inch GaN-on-Si discrete and Integrated power devices: bringing efficiency and operating frequency to the next level



Dr Denis Marcon

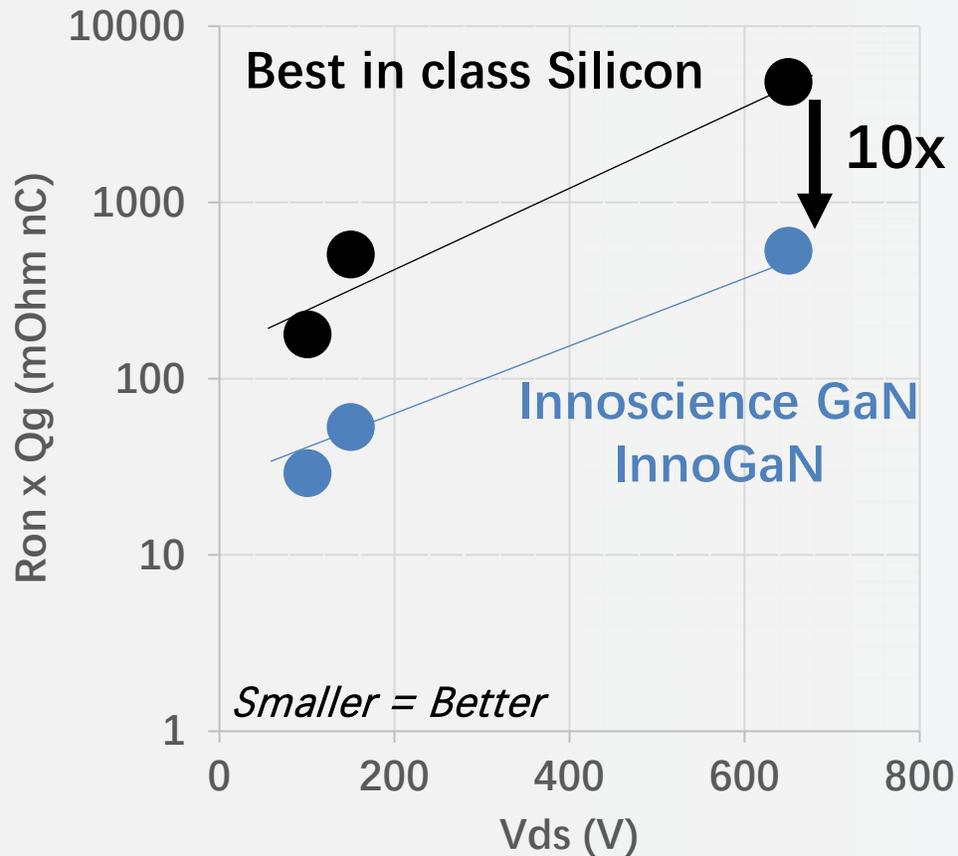
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The beauty of GaN-based power devices

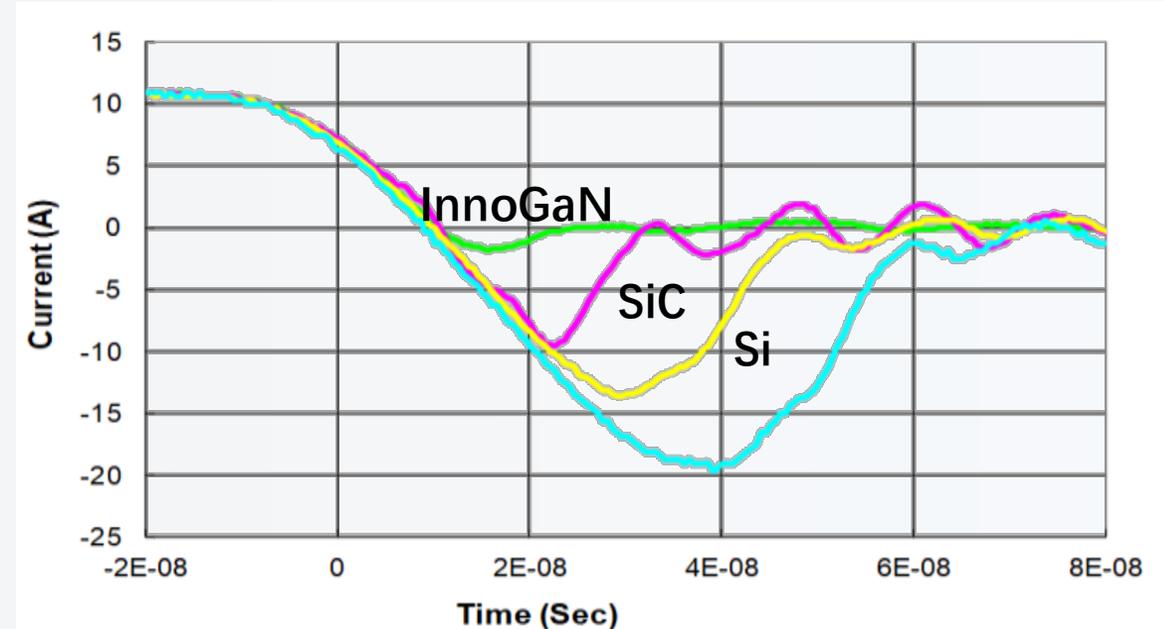


Ron x Qg is 10x better than Silicon



Efficiency is maintained at high frequency

Reverse Recovery @ $T_j=100^\circ\text{C}$



Absence of the body diode

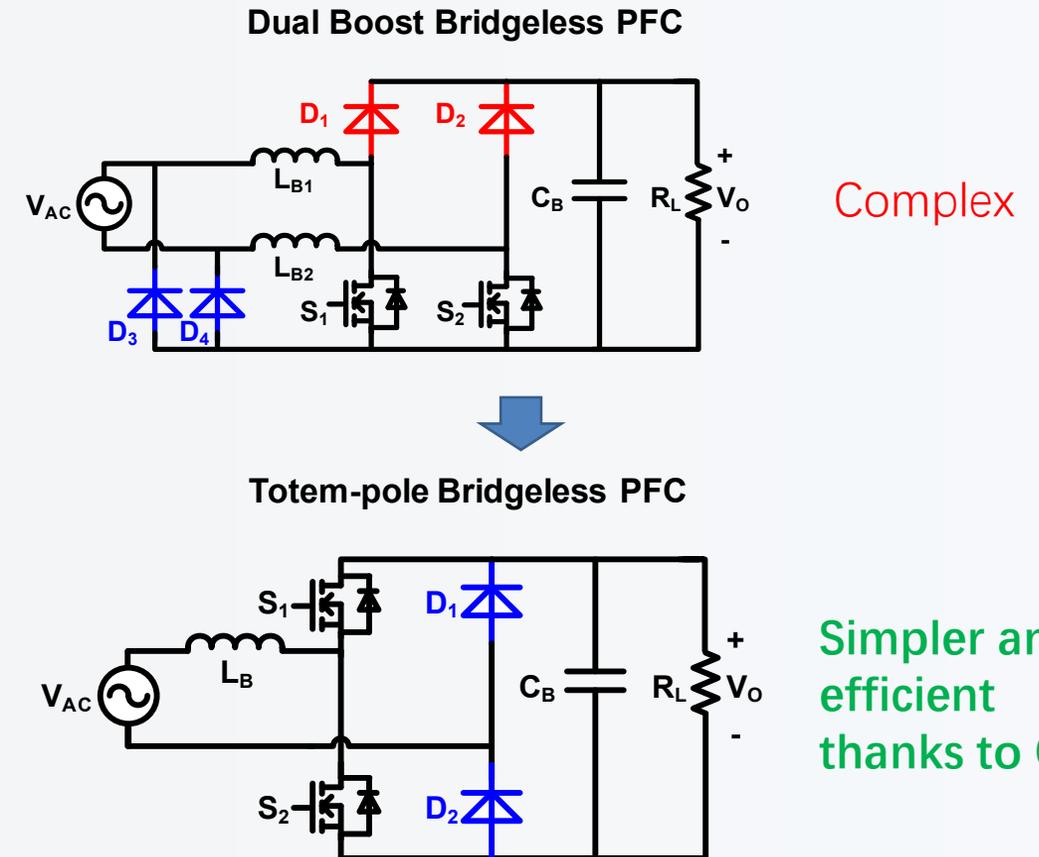
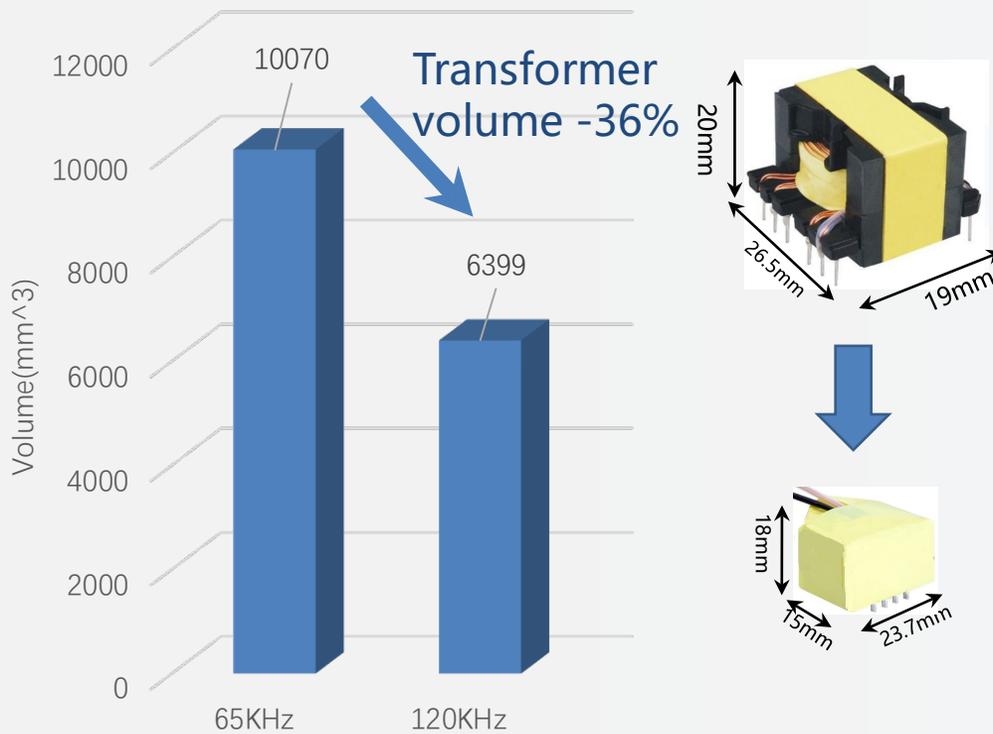


No reverse recovery current

What does this mean?

Higher switching frequency means shirking of the passives components

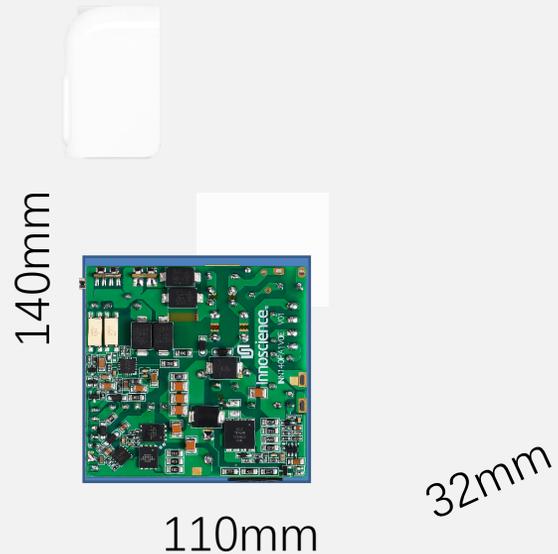
No reverse recovery means simpler and cheaper system topology



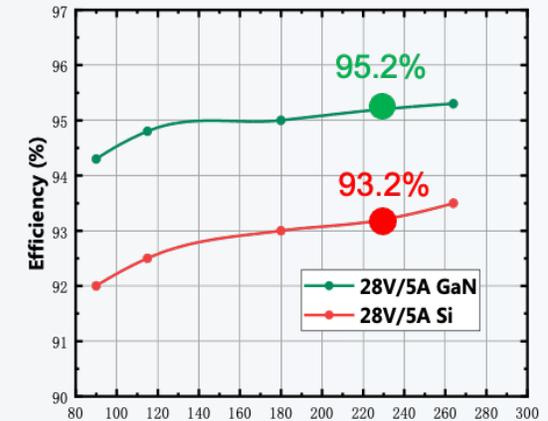
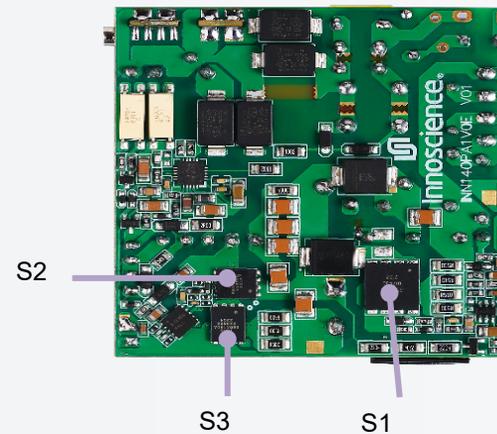
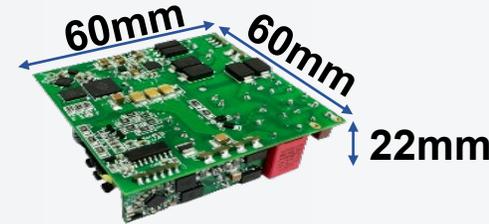
Let me give you a concrete example: 140W charger

State-of-the-art
140W charger¹

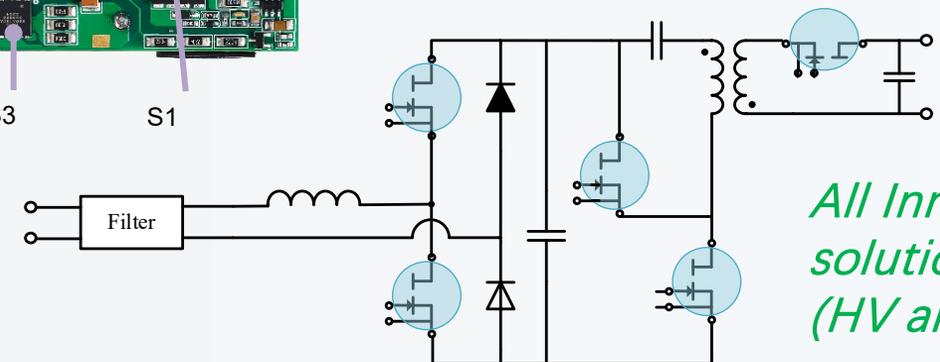
11.41W/in³
0.7W/cm³



InnoGaN solution: power density of 1.76W/cm³ (29W/in³)
More >2x higher power density wrt Si commercial solution



Totem pole PFC + AHB



*All InnoGaN
solution
(HV and LV)*

[1] <https://inf.news/en/digital/15977116257b89b184ae41f0d65dbb7a.html>

GaN market & applications examples

Consumer

Mobile



Charger



Computing



Class-D Audio



Industrial

Motor control



PV & Storage



PFC & Power Supplies



Communication

48V Bus



Server



Base stations



E-Mobility

Fast chargers



Motor Drives



BMS



LED Lighting

Smart Building



Street Lighting



Smart Agriculture



Automotive

Lidar



OBC



48V Aux Power



GaN brings efficiency and power density to the next level with optimum solution cost !

Status of GaN power device suppliers (today)

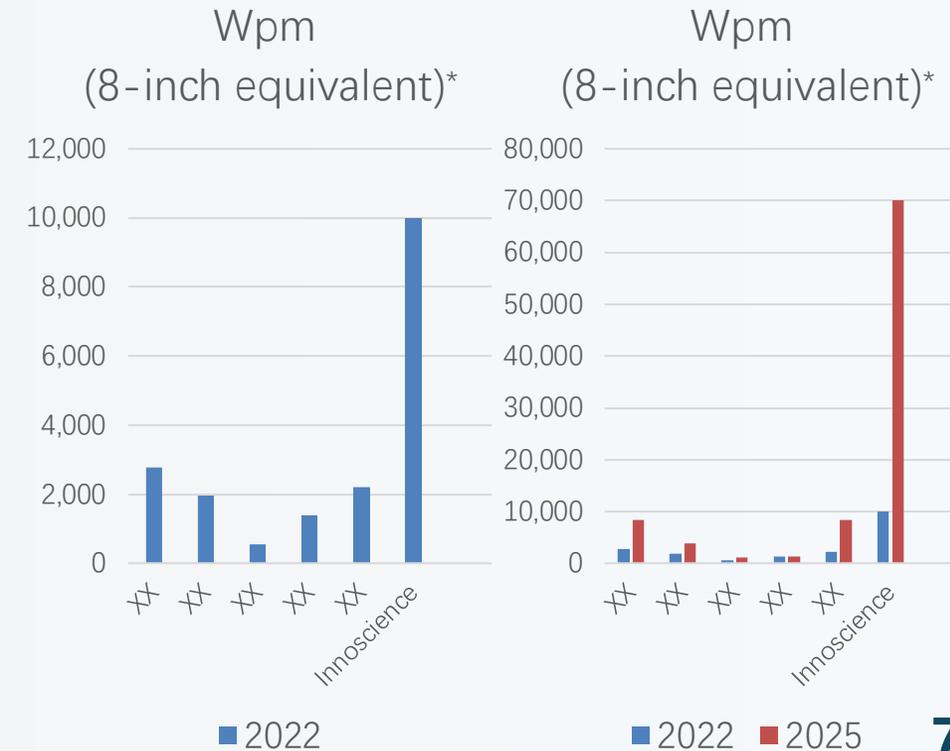
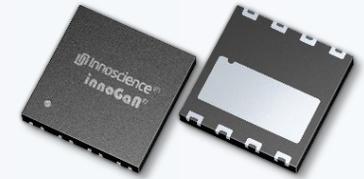
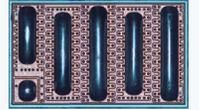
- Limits the ability to differentiate
- How to add value to a discrete device in a foundry process?
- Inherent trend to innovate by adding on-GaN functionality
- **Constraining GaN growth**

	100% GaN focus	Legacy Si products	Technology development	Product innovation	High volume cost effective GaN production
Fabless startups	Green	Green	Yellow	Yellow	Red
Si power IDMs	Red	Red	Green	Green	Yellow
Innoscience: 100% GaN IDM	Green	Green	Green	Green	Green

- Internal competition
- Prioritization
- Not enough cost competitive
- Limited production capacity
- **Constraining GaN growth**

Innoscience is the GaN game changer: 100% GaN IDM

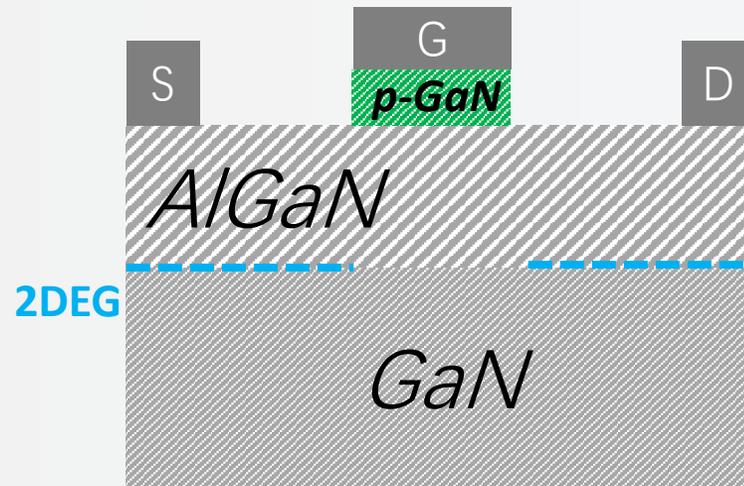
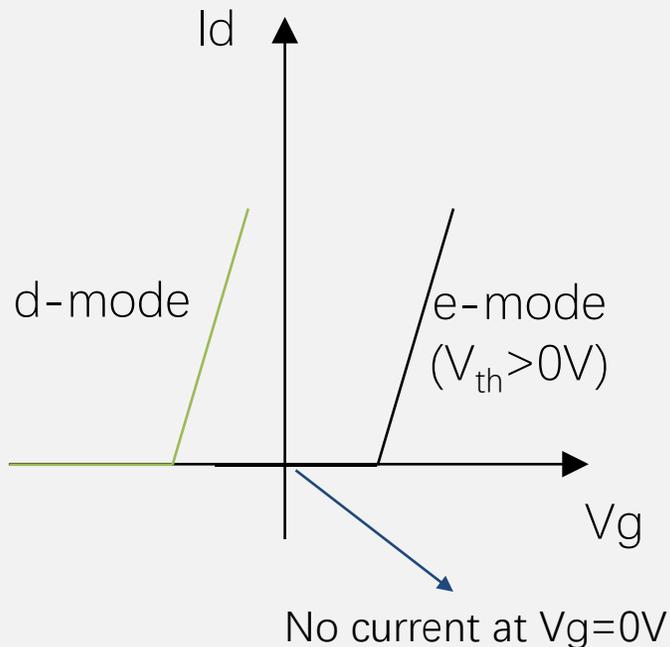
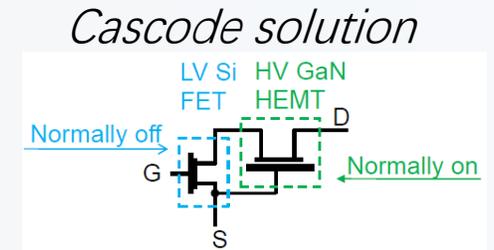
- Wide portfolio: HV (650V), MV (100V-150V) and LV (<100V) GaN power devices
- #2 large 8-inch Silicon-like high-throughput fabs: largest GaN capacity worldwide
- >1500 people 100% focused on GaN
- >100Mpcs shipped so far
- 8-inch + Economy of scale to slash the cost of GaN (adoption barrier)



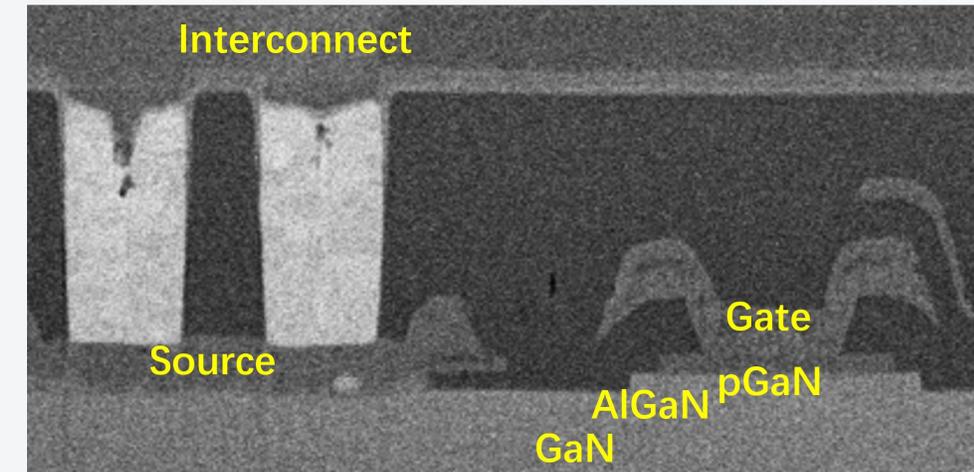
*Source: Yole report, "GaN Power 2021: Epitaxy, Devices, Applications and Technology Trends"

InnoGaN is normally-off/e-mode

- GaN-based devices are naturally normally-on/depletion mode (d-mode)
- **Power device market demands normally-off devices:**
 - Co-packaging of the GaN d-mode with a LV Si MOS or other Si IC
 - True normally-off/enhancement mode (e-mode) device technology
- **Innoscience device technology is normally-off/enhancement-mode (E-mode) based on p-GaN**

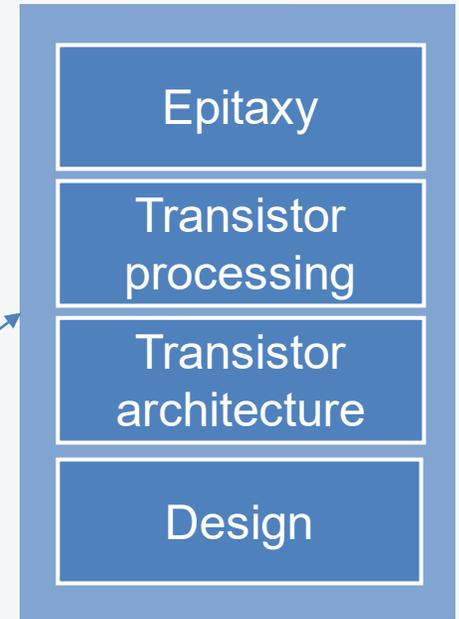
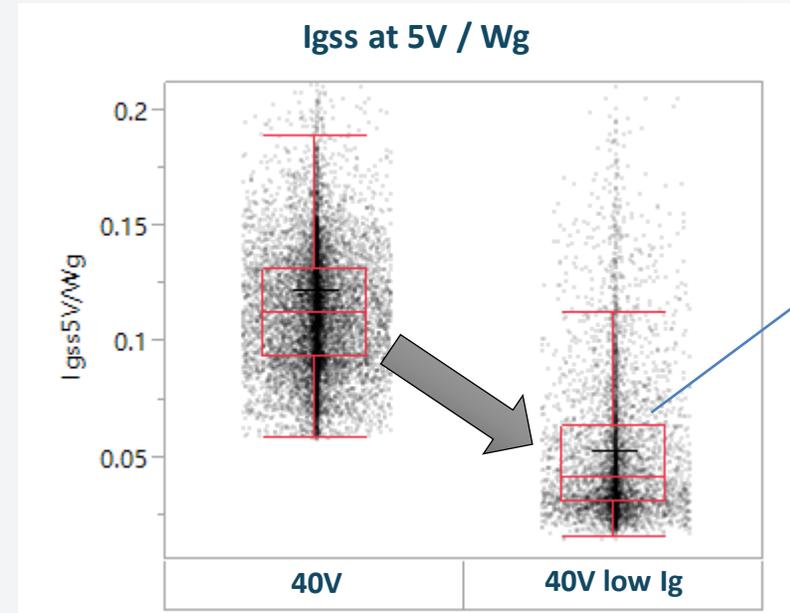
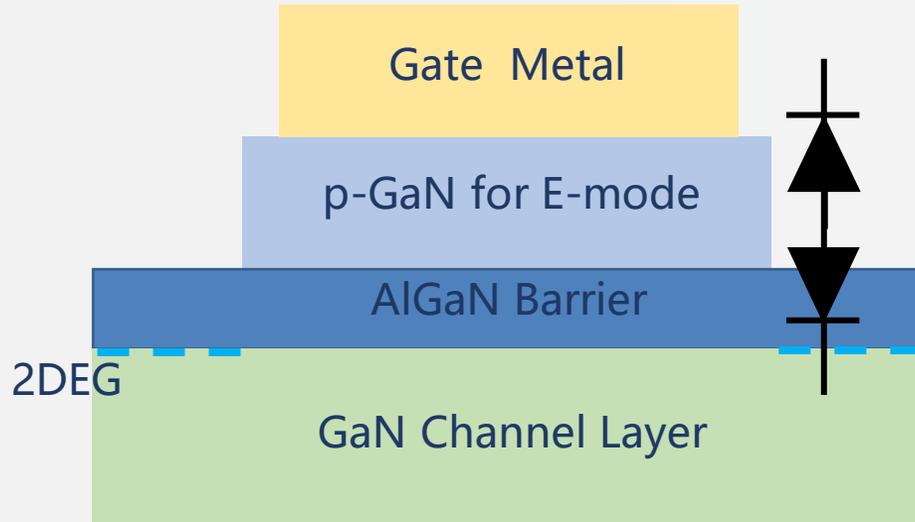


A p-GaN layer below the gate lift-up the conduction band (from the Fermi level) only below the gate to realize e-mode operation.



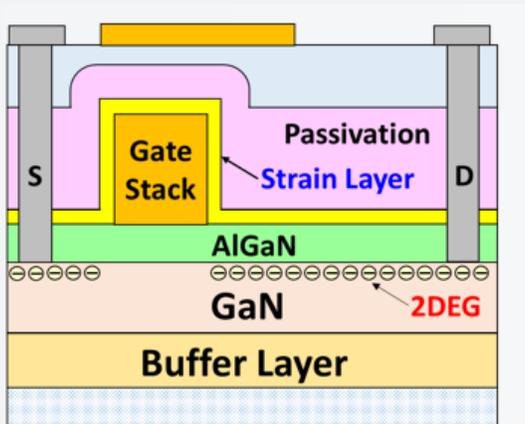
Why IDM? Gate leakage breakthrough on E-mode GaN

p-GaN HEMT Gate structure
(Back-to-back diodes in series)

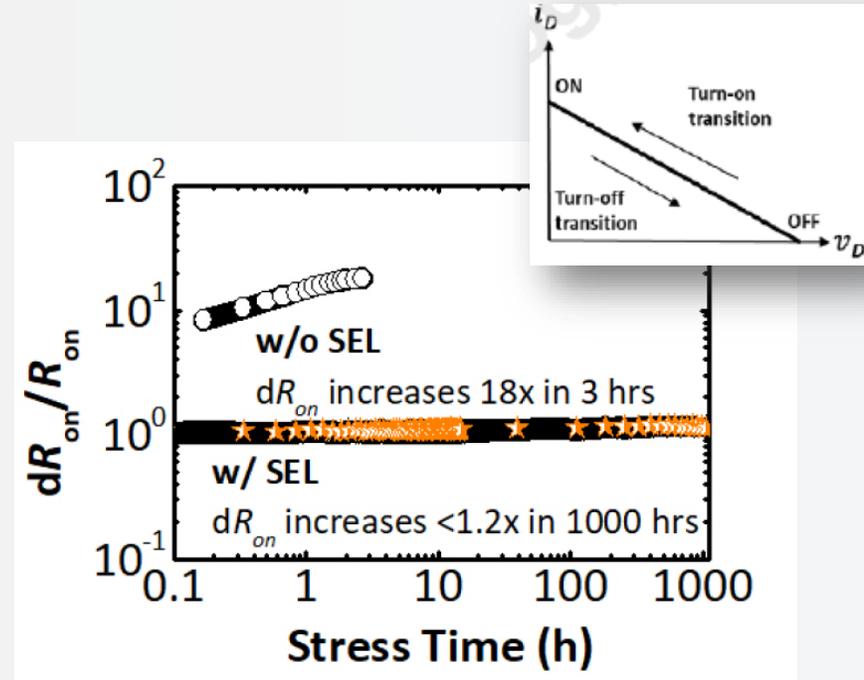


- E-mode GaN devices do not have an oxide below the gate
- Need to co-optimize epi, processing, architecture, design etc..
- **~10x reduction of gate leakage**
 - **<3 μA at 85 °C throughout the device lifetime \rightarrow ok inside smartphone**

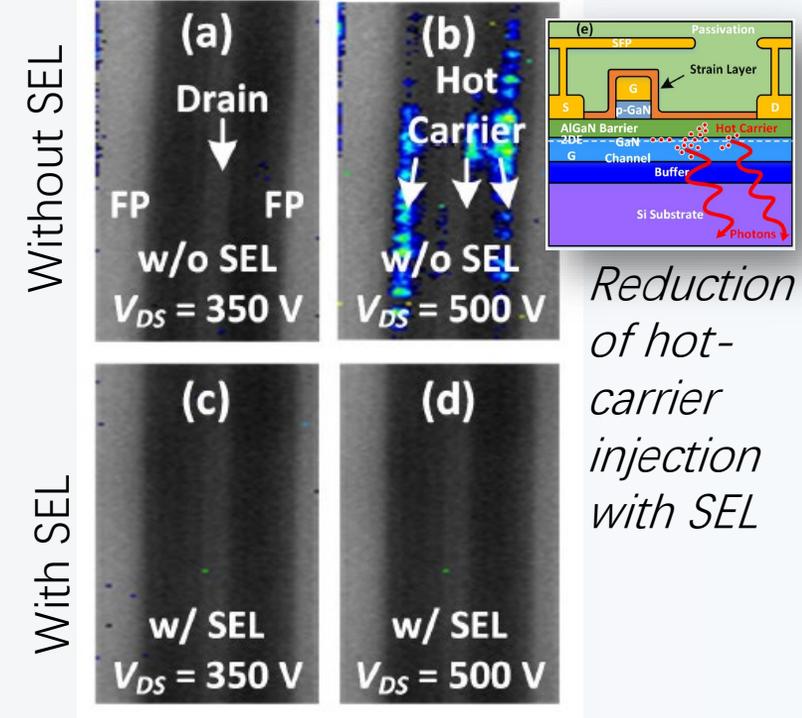
Technology differentiator: strain enhance layer (SEL)



- Gate Formation
- **Strain Enhancement Layer Deposition**
- Passivation Deposition
- Ohmic Contact Formation
- Inter-layer Dielectric Deposition
- Interconnect Contact Formation
- Metal-1 Formation
- Inter-metal Dielectric Deposition
- Via and Substrate Contact Formation
- Metal-2 Formation
- Passivation Formation



Comparison of dR_{on} without and with the SEL under the HS test with $V_{DS} = 600$ V, $V_{GS} = 6$ V, and $f_s = 100$ kHz.

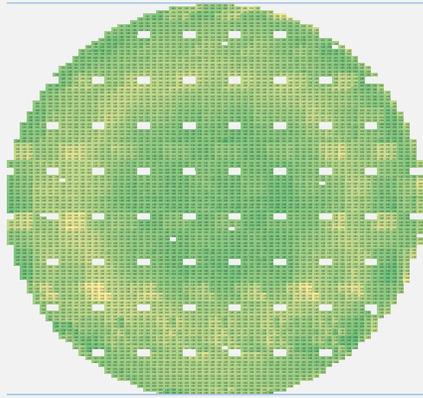


Wafer-level switching strain system embedded into the Emission Microscope (EMMI) to detect the electroluminescence of device in situ.

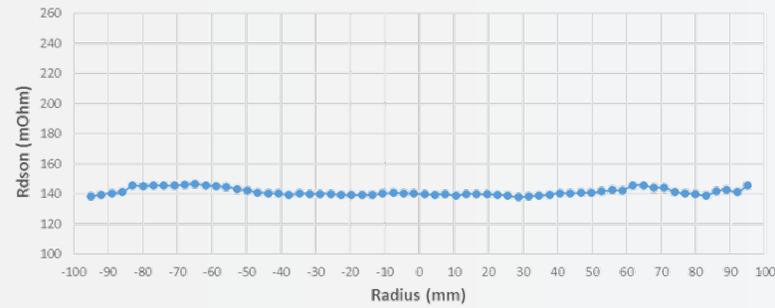
Technology maturity

Both Epitaxy as well as Device processing have been optimized to obtain high reproducibility and yield

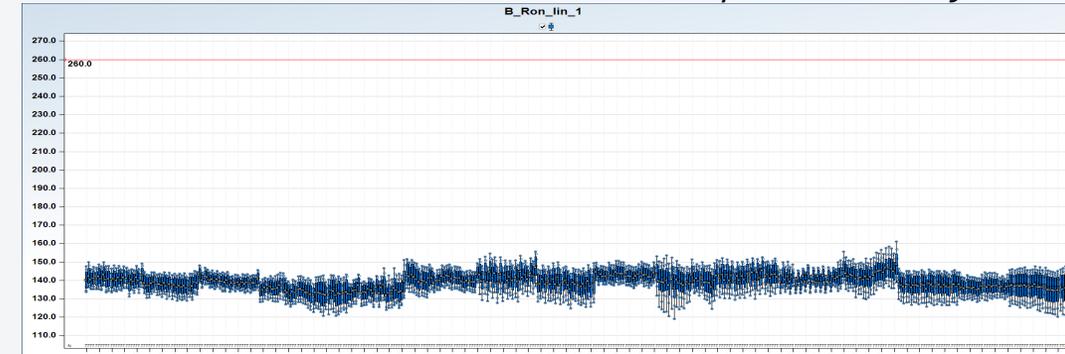
$R_{DS(on)}$



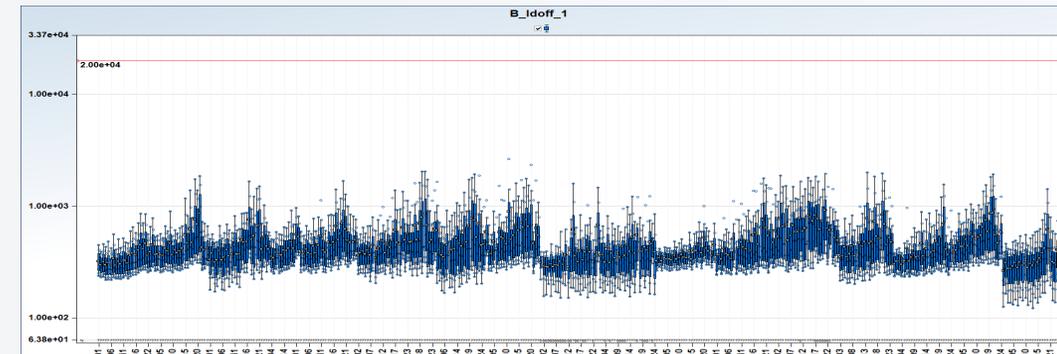
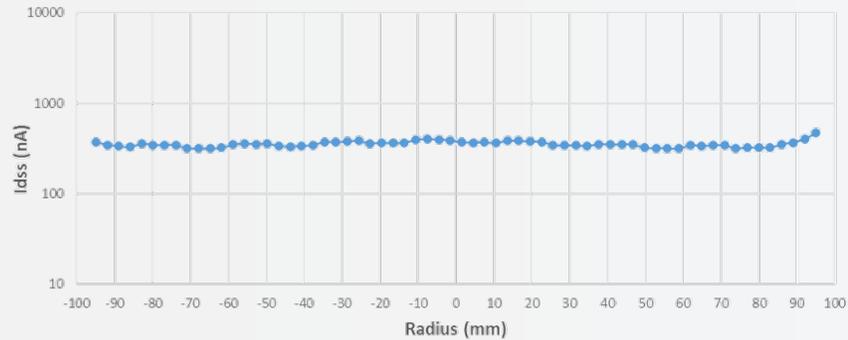
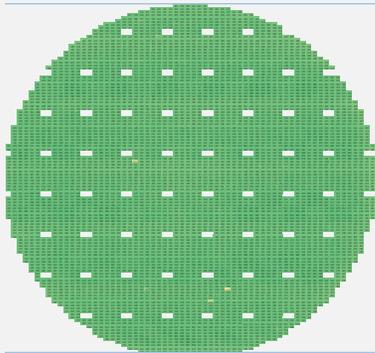
Excellent within wafer uniformity



Excellent wafer-to-wafer reproducibility



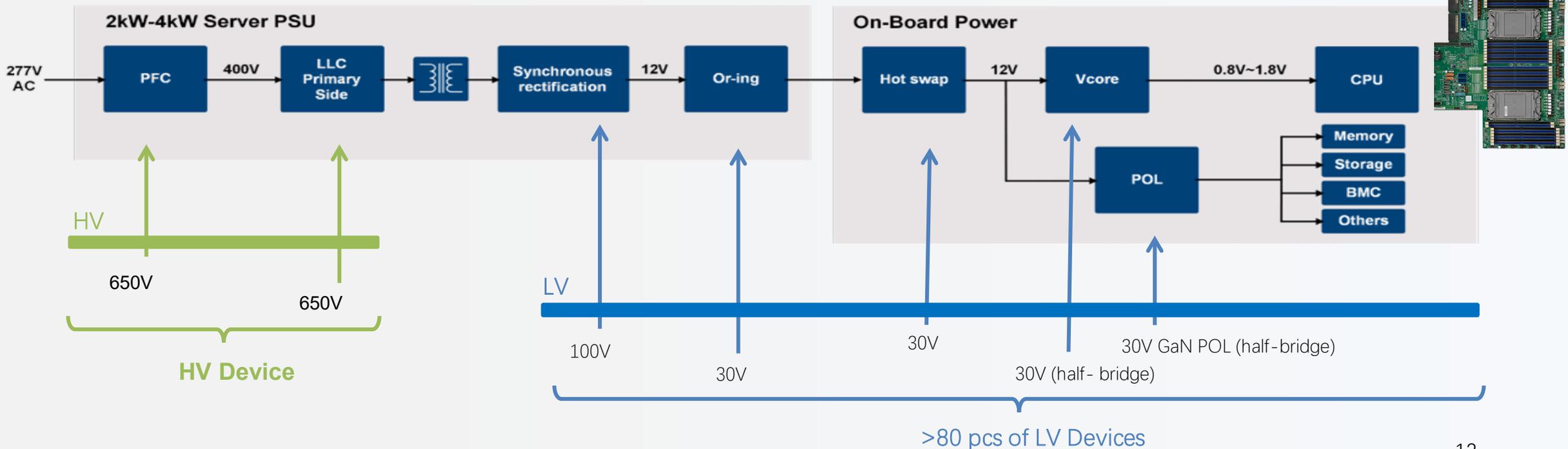
I_{dss}



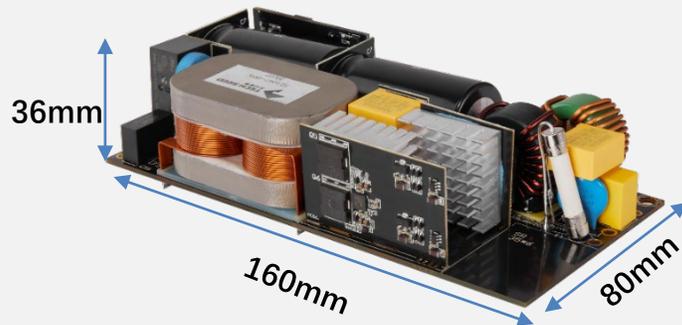
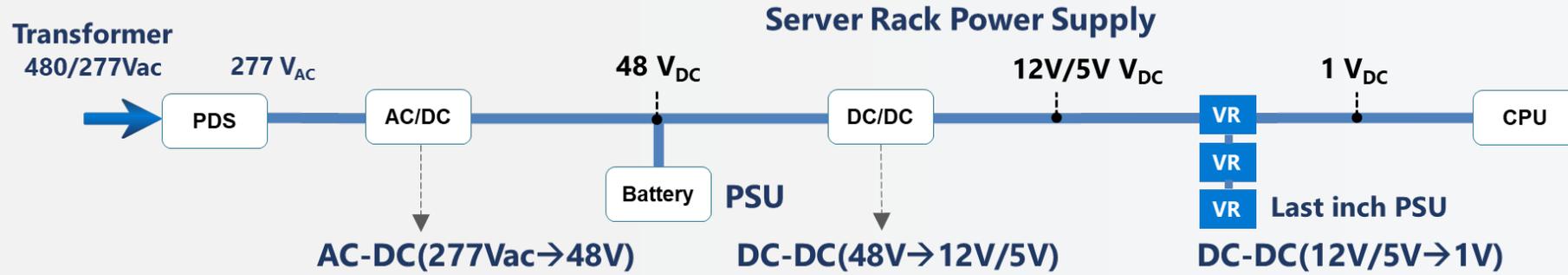
Case study: Data center



- Data center is a huge and growing market
- Power hungry → efficiency is top priority (save CO₂ and \$\$\$)
- Solution Size is important too (more space for computing unit)
- In need of big volume capacity and price competitiveness



InnoGaN in datacenters: AC-DC conversion



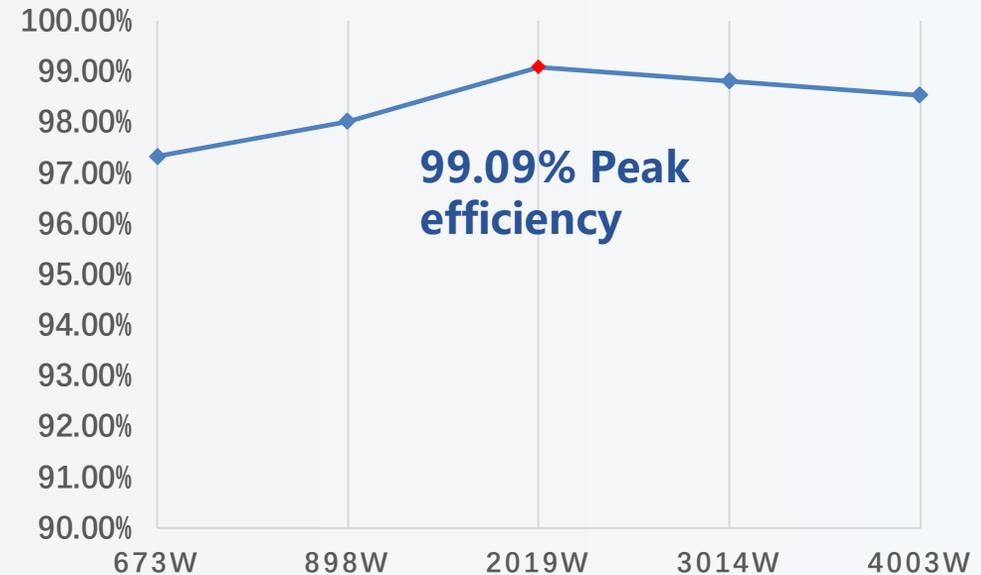
142W/in³

Totem Pole PFC

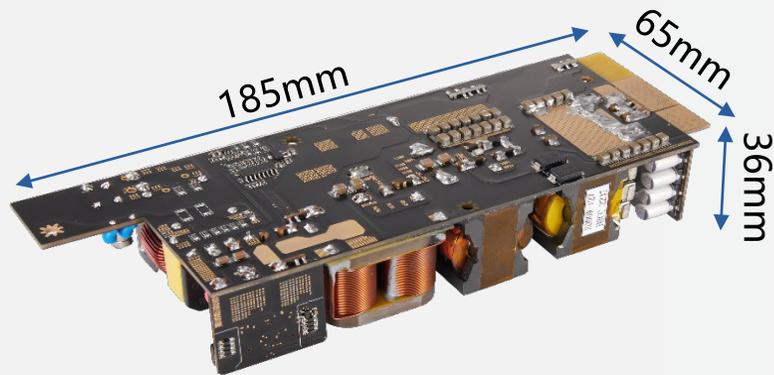
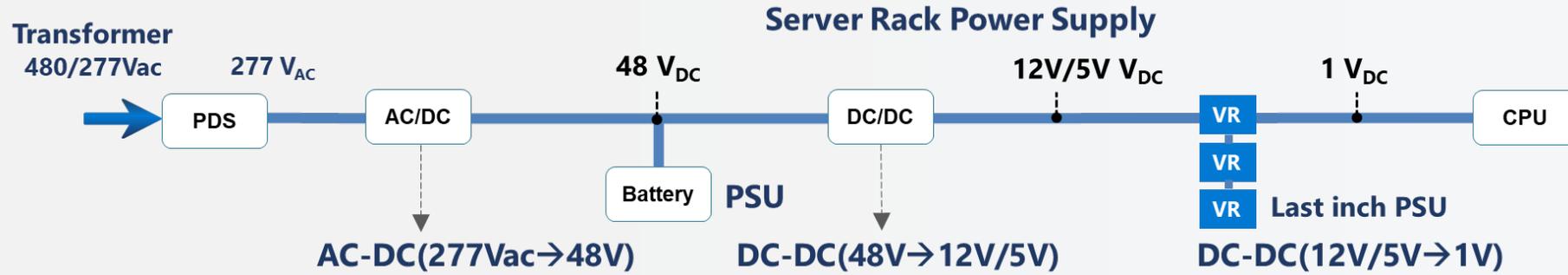
650V/30mOhm



**Standard packages
DFN and TOLL**



InnoGaN in datacenters: AC-DC conversion

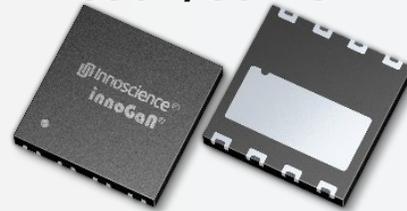


Totem Pole PFC+LLC

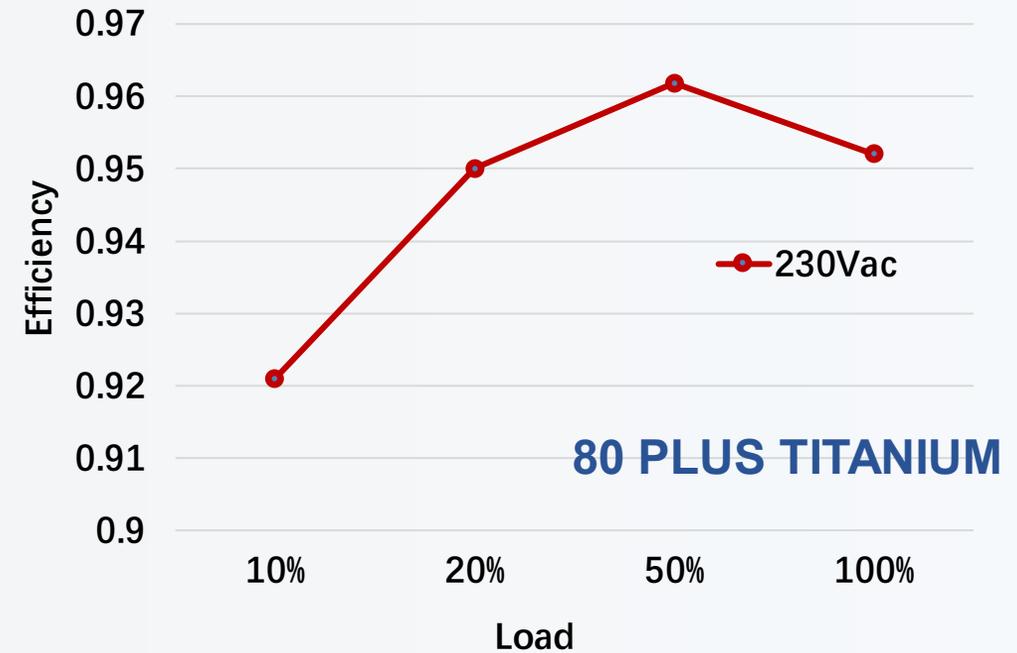
650V/30mOhm



650V/80mOhm

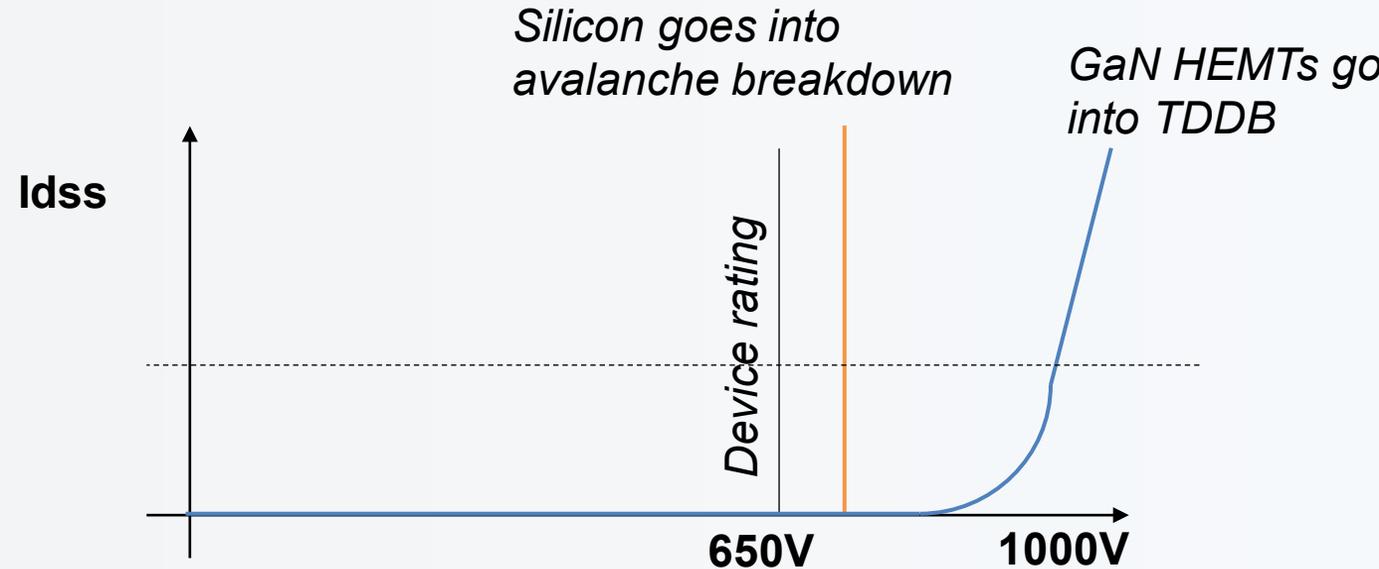


**Standard packages
DFN and TOLL**



Transient voltage rating

- In power switching system transient voltages or spikes beyond the device rating are expected
- Silicon has avalanche rating but not in today GaN HEMTs
- Yet, GaN HEMTs need to have the ability to sustain transient voltage and spikes



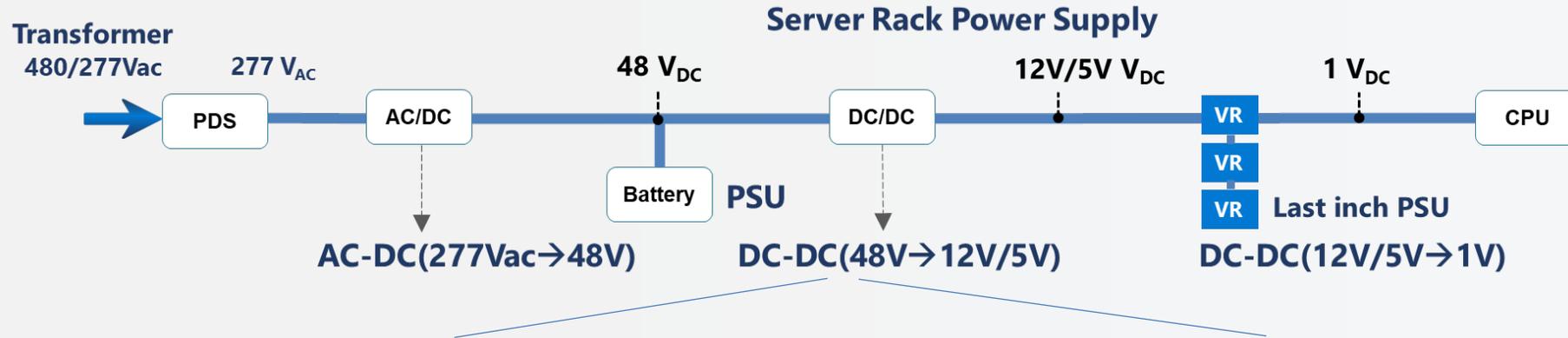
Parameter	Symbol	Values	Unit	Note/Test Condition
Drain source voltage	$V_{DS, max}$	700	V	$V_{GS} = 0 V$, $T_j = -55\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$
Drain source voltage transient ¹	$V_{DS, transient}$	800	V	$V_{GS} = 0 V$
Drain source voltage, pulsed ²	$V_{DS, pulse}$	750	V	$T_j = 25\text{ }^{\circ}\text{C}$; total time < 10 h
				$T_j = 125\text{ }^{\circ}\text{C}$; total time < 1 h

InnoGaN can be safely used and sustain transient voltages well above their maximum rating

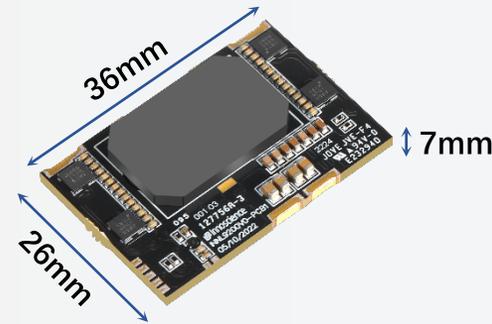
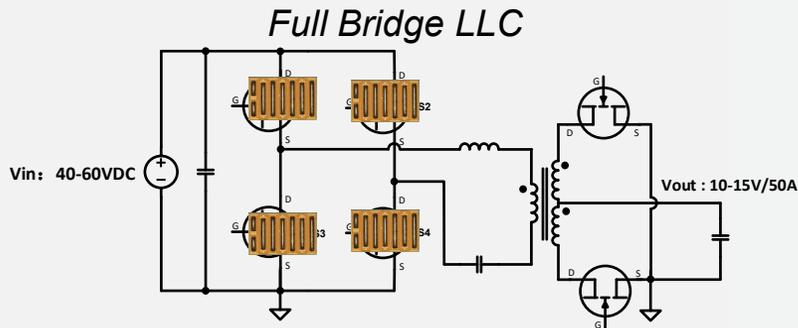
1. $V_{DS, transient}$ is intended for non-repetitive events, $t_{PULSE} < 200\text{ }\mu\text{s}$.

2. $V_{DS, pulse}$ is intended for repetitive pulse, $t_{PULSE} < 100\text{ ns}$.

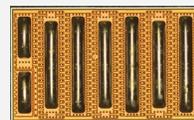
InnoGaN in datacenters: 48V-12V conversion



600W DC-DC 48V to 12V 1MHz Power Module

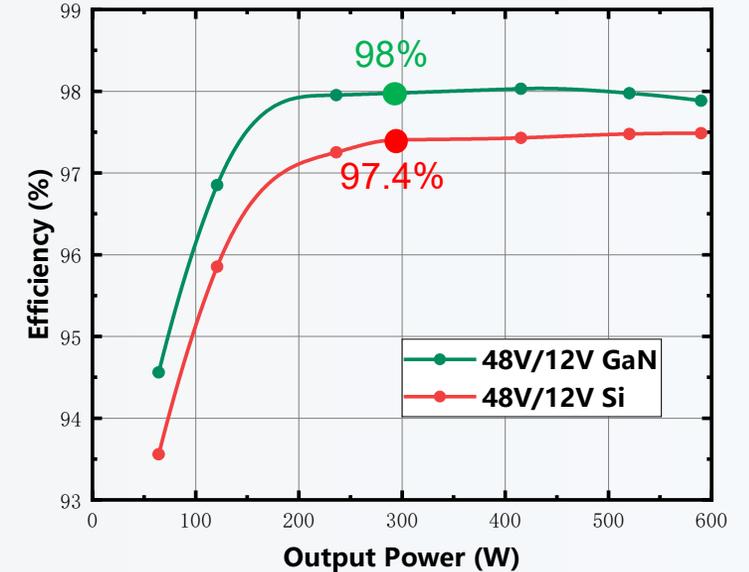


Higher Power Density: 2100W/in³

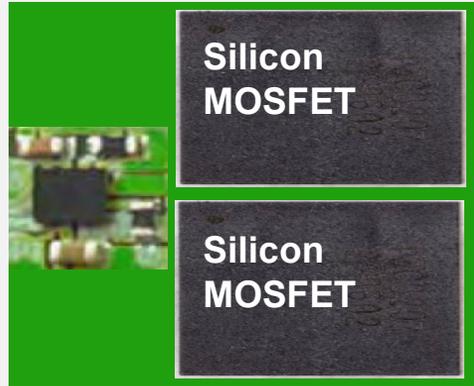


100V/3.2mOhm

	INN100W032A
V _{DS} (V)	100
R _{DS(ON)} (mΩ)	2.4/3.2
R _{DS(ON)} *Q _g (mR*nC)	29.4
Die Size(mm)	3.5 x 2.1



Introduction to ISG3201: Half-bridge and driver in one package



Discrete Si
11mmx11mm

Down 65%

Discrete GaN
8mmx5mm

Performance and flexibility

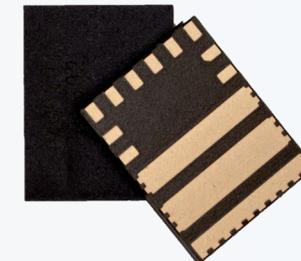
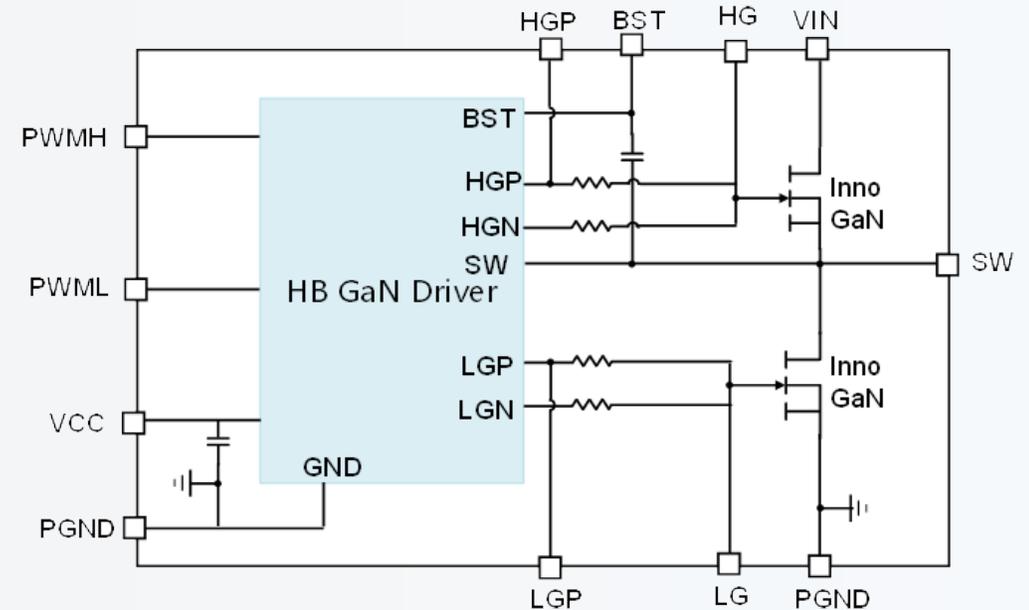
Down 20%

ISG3201
6.5mmx5mm

(even higher) Performance and easy to use /soldering

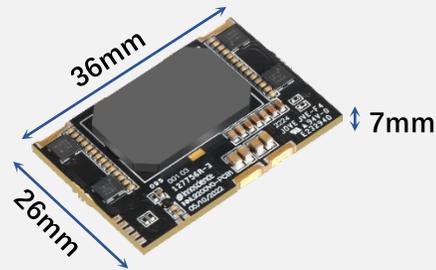
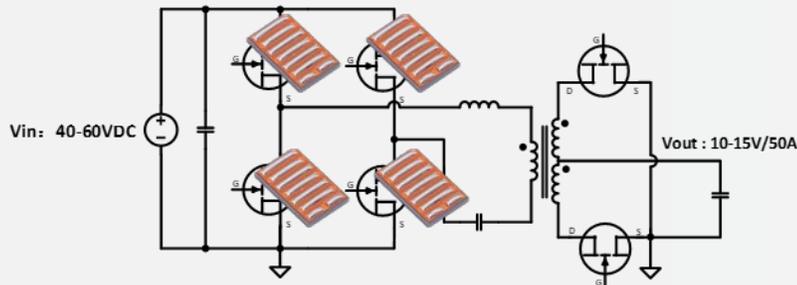
Down 73%

ISG3201 Half-bridge (3.2mOhm+3.2mOhm) + Driver



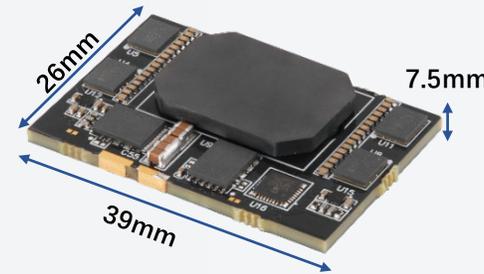
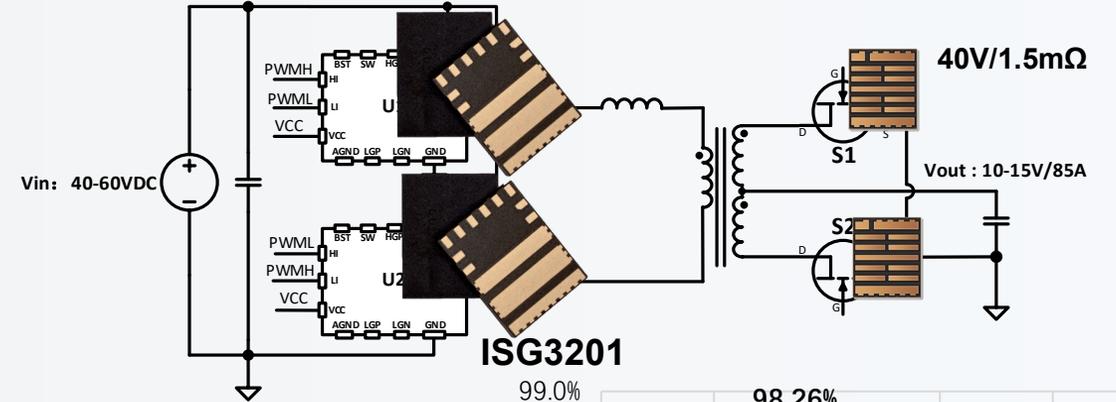
Increasing the performance with SolidGaN

600W DC-DC 48V to 12V 1MHz

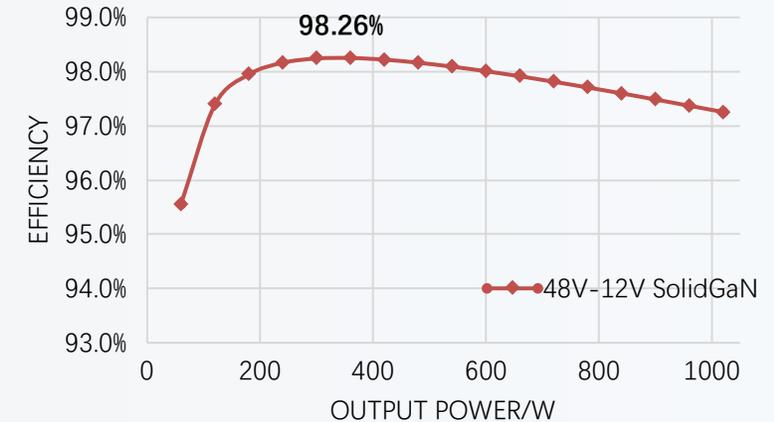


Higher Power Density: 2100W/in³
Peak Efficiency: 98%

1000W 48V-12V DC-DC Power Module 1MHz

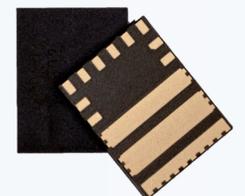


High Power Density: 2150W/in³



Conclusion

- **GaN power devices are a (much) better switch than Silicon devices**
- **Any power conversion system can be made smaller, more efficient and even cheaper with GaN power devices**
- **Innoscience is the game changer bringing GaN power devices into mass production**
 - 100% focused IDM
 - Large 8-inch high-throughput manufacturing facilities
 - Slashing price and addressing mass volume needs
- **InnoGaN devices are robust and reliable**
 - e.g. Avalanche rating is tackled by transient voltage rating specifications
- **Discrete vs AND Integrated solutions: engineers select what they like**





Thank you

Dr Denis Marcon

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